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<b>Notice of References Cited</b>	Application/Control No. <b>09/964,449</b>		Applicant(s)/Patent Under Reexam <b>Nakamura et al.</b>	
	Examiner <b>A. Farah</b>		Art Unit <b>3739</b>	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Name	Classification <sup>2</sup>	
x	A 6,190,374 B1	2/2001	Amano et al.	606	005
	B 6,416,179 B1	7/2002	Lieberman et al.	351	212
	C 6,364,483 B1	4/2002	Grossinger et al.	351	161
	D 5,786,883	7/1998	Miller et al.	351	162
	E 6,296,867 B1	10/2001	Peyman	424	429
	F				
	G				
	H				
	I				
	J				
	K				
	L				
	M				

**FOREIGN PATENT DOCUMENTS**

*	Document Number <small>Country Code-Number-Kind Code</small>	Date <small>MM-YYYY<sup>1</sup></small>	Country	Name	Classification <sup>2</sup>	
	N					
	O					
	P					
	Q					
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**NON-PATENT DOCUMENTS**

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